Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	· · ·
10/605,650	CHANG, YEN-JEN	
Examiner	Art Unit	

2627

Brian E. Miller

	SEARCHED			
Class	Subclass	Date	Examiner	
720	692, 694	10/12/2006	BEM	
720	698, 688	10/12/2006	ВЕМ	
updated	as above	1/17/2006	BEM	
720	697, 611	1/17/2007	ВЕМ	
		•		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
720	698, 692	1/17/2007	BEM
720	611	1/17/2007	вем
=	EAST PGPUB (interference) search		ВЕМ

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST Search	10/12/2006	ВЕМ
PLUS Search	10/13/2006	ВЕМ
EAST updated Search (enclosed)	1/17/2007	BEM